

## Full Bridge IGBT and MOSFET MTP Power Module



MTP


**RoHS**  
COMPLIANT

### FEATURES

- Generation 4 warp speed IGBT and power MOSFET technology
- HEXFRED® antiparallel diodes with ultrasoft reverse recovery
- Very low conduction and switching losses
- Operating frequency up to 100 kHz
- Designed and qualified for industrial level
- Material categorization: For definitions of compliance please see [www.vishay.com/doc?99912](http://www.vishay.com/doc?99912)

### BENEFITS

- Optimized for welding, UPS and SMPS applications
- Low EMI, requires less snubbing
- Direct mounting to heatsink
- PCB solderable terminals
- Very low stray inductance design for high speed operation

PRODUCT SUMMARY	
<b>HALF BRIDGE POWER MOSFET</b>	
$V_{DSS}$	650 V
$R_{DS(on)}$ typical at $I_D = 40$ A	35 m $\Omega$
$I_D$ at $T_C = 80$ °C	41 A
<b>HALF BRIDGE WARP IGBT</b>	
$V_{CES}$	600 V
$V_{CE(on)}$ typical at $I_C = 25$ A	2.18 V
$I_C$ at $T_C = 80$ °C	46 A

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	SYMBOL	TEST CONDITIONS		MAX.	UNITS
Operating junction temperature	$T_J$			150	°C
Storage temperature range	$T_{Stg}$			- 40 to 150	
$V_{RMS}$ Insulation voltage	$V_{ISOL}$	AC 1.2 s		3500	V
<b>Q1, Q2 POWER MOSFET</b>					
Drain to source voltage	$V_{DSS}$			650	V
Gate to source voltage	$V_{GS}$			25	
Pulsed drain current	$I_{DM}^{(1)}$			270	A
Single pulse avalanche energy	$E_{AS}$	$T_C = 25$ °C; $I_D = I_{AR}$ , $V_{DD} = 50$ V		2000	mJ
Avalanche current repetitive	$I_{AR}$	pulsed width limited by $T_J$ max.		15	A
Peak diode recovery voltage slope	$dV/dt^{(2)}$			15	V/ $\mu$ s
Continuous drain current	$I_D$	$T_C = 25$ °C	$V_{GS} = 10$ V	52	A
		$T_C = 80$ °C		41	
Power dissipation	$P_D$	$T_C = 25$ °C		284	W
		$T_C = 80$ °C		159	
<b>Q3, Q4 WARP IGBT</b>					
Collector to emitter voltage	$V_{CES}$			600	V
Gate to emitter voltage	$V_{GES}$			20	
Pulsed collector current	$I_{CM}$			200	A
Clamped inductive load current	$I_{LM}$			200	
Continuous collector current	$I_C$	$T_C = 25$ °C		67	
		$T_C = 80$ °C		43	
Power dissipation	$P_D$	$T_C = 25$ °C		211	W
		$T_C = 80$ °C		118	



<b>ABSOLUTE MAXIMUM RATINGS</b>				
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
<b>D1, D2, AP DIODE OF WARP IGBT</b>				
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	73	A
		$T_C = 80\text{ }^\circ\text{C}$	48	
Peak diode forward current	$I_{FSM}$	$T_C = 25\text{ }^\circ\text{C}$	260	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	143	W
		$T_C = 80\text{ }^\circ\text{C}$	80	
<b>SOURCE DRAIN (MOSFET BODY DIODE)</b>				
Continuous source current	$I_S$	$T_C = 25\text{ }^\circ\text{C}$	52	A
Pulsed source current	$I_{SM}$	$T_C = 25\text{ }^\circ\text{C}$	360	

**Notes**

- (1) Pulse width limited by safe operating area
- (2)  $I_{SD} < 69\text{ A}$ ,  $dI/dt = 400\text{ A}/\mu\text{s}$ , peak  $V_{SD} < V_{(BR)DSS}$

<b>ELECTRICAL SPECIFICATIONS (<math>T_J = 25\text{ }^\circ\text{C}</math> unless otherwise specified)</b>						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q1, Q2 POWER MOSFET</b>						
Drain to source breakdown voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}$ , $I_D = 250\text{ }\mu\text{A}$	650	-	-	V
Static drain to source on resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}$ , $I_D = 50\text{ A}$	-	35	44	$\text{m}\Omega$
		$V_{GS} = 10\text{ V}$ , $I_D = 50\text{ A}$ , $T_J = 150\text{ }^\circ\text{C}$	-	-	104	$\text{m}\Omega$
Gate threshold voltage	$V_{GS(th)}$	$V_{GE} = V_{GS}$ , $I_D = 0.25\text{ mA}$	2.8	4	5.4	V
Drain to source leakage current	$I_{DSS}$	$V_{DS} = 650\text{ V}$ , $V_{GS} = 0\text{ V}$	-	-	50	$\mu\text{A}$
		$V_{DS} = 650\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$	-	-	5.0	$\text{mA}$
Gate to source forward leakage	$I_{GSS}$	$V_{GS} = 25\text{ V}$	-	-	100	nA
Gate to source reverse leakage		$V_{GS} = -25\text{ V}$	-	-	-100	
Intrinsic gate resistance	$R_g$	$f = 1\text{ MHz}$ , open drain	-	1.2	-	$\Omega$
Total gate charge	$Q_g$	$I_D = 35\text{ A}$	-	200	-	nC
Gate to source charge	$Q_{gs}$	$V_{DD} = 520\text{ V}$	-	60	-	
Gate to drain (Miller) charge	$Q_{gd}$	$V_{GS} = 10\text{ V}$	-	70	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 325\text{ V}$ $L = 500\text{ }\mu\text{H}$ , $I_D = 40\text{ A}$ $R_g = 5\text{ }\Omega$ , $V_{GS} = 10\text{ V}$ , $T_J = 125\text{ }^\circ\text{C}$	-	165	-	ns
Rise time	$t_r$		-	44	-	
Turn-off delay time	$t_{d(off)}$		-	148	-	
Fall time	$t_f$		-	30	-	
Input capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}$	-	9800	-	pF
Output capacitance	$C_{oss}$	$V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$	-	200	-	
<b>SOURCE DRAIN (MOSFET BODY DIODE)</b>						
Forward voltage	$V_{SD}$	$I_S = 34\text{ A}$ , $V_{GS} = 0\text{ V}$	-	-	1.0	V
<b>Q3, Q4 WARP IGBT</b>						
Collector to emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE} = 0\text{ V}$ , $I_C = 250\text{ }\mu\text{A}$	600	-	-	V
Collector to emitter voltage	$V_{CE(on)}$	$V_{GE} = 15\text{ V}$ , $I_D = 25\text{ A}$	-	2.18	2.83	
		$V_{GE} = 15\text{ V}$ , $I_C = 25\text{ A}$ , $T_J = 150\text{ }^\circ\text{C}$	-	1.75	2.34	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$ , $I_C = 0.25\text{ mA}$	2.8	4.9	6.2	V
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}$ , $I_C = 1\text{ mA}$ ( $25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$ )	-	-12	-	$\text{mV}/^\circ\text{C}$
Forward transconductance	$g_{fe}$	$V_{CE} = 20\text{ V}$ , $I_C = 25\text{ A}$	-	49	-	S
Zero gate voltage collector current	$I_{CES}$	$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$	-	-	250	$\mu\text{A}$
		$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$ , $T_J = 125\text{ }^\circ\text{C}$	-	-	5.0	$\text{mA}$
Gate to emitter leakage current	$I_{GES}$	$V_{GE} = \pm 20\text{ V}$ , $V_{CE} = 0\text{ V}$	-	-	$\pm 100$	nA
<b>D1, D2, AP DIODE OF WARP IGBT</b>						
Forward voltage drop	$V_{FM}$	$I_F = 25\text{ A}$	-	1.3	1.41	V
		$I_F = 25\text{ A}$ , $T_J = 150\text{ }^\circ\text{C}$	-	1.11	1.29	



<b>SWITCHING CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q3, Q4 WARP IGBT</b>						
Total gate charge (turn-on)	$Q_g$	$I_C = 25\text{ A}$	-	175	-	nC
Gate to emitter charge (turn-on)	$Q_{ge}$	$V_{CC} = 400\text{ V}$	-	27	-	
Gate to collector charge (turn-on)	$Q_{gc}$	$V_{GE} = 15\text{ V}$	-	71	-	
Turn-on switching loss	$E_{on}$	$I_C = 25\text{ A}$	-	0.21	-	mJ
Turn-off switching loss	$E_{off}$	$V_{CC} = 400\text{ V}, V_{GE} = 15\text{ V}$	-	0.15	-	
Total switching loss	$E_{tot}$	$R_g = 5\text{ }\Omega, L = 500\text{ }\mu\text{H}$	-	0.36	-	
Turn-on switching loss	$E_{on}$	$I_C = 25\text{ A}$	-	0.33	-	mJ
Turn-off switching loss	$E_{off}$	$V_{CC} = 400\text{ V}, V_{GE} = 15\text{ V}$	-	0.36	-	
Total switching loss	$E_{tot}$	$R_g = 5\text{ }\Omega, T_J = 125\text{ }^\circ\text{C}, L = 500\text{ }\mu\text{H}$	-	0.69	-	
<b>D1, D2, AP DIODE OF WARP IGBT</b>						
Diode reverse recovery time	$t_{rr}$	$V_{RR} = 400\text{ V}$	-	118	-	ns
Diode peak reverse current	$I_{rr}$	$I_F = 25\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	13.5	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 200\text{ A}/\mu\text{s}$	-	760	-	nC
<b>SOURCE DRAIN (MOSFET BODY DIODE)</b>						
Diode reverse recovery time	$t_{rr}$	$I_{SD} = 34.5\text{ A}$	-	563	-	ns
Diode reverse current	$I_{rr}$	$V_{DD} = 100\text{ V}$	-	35	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 100\text{ A}/\mu\text{s}$	-	9500	-	nC

<b>THERMISTOR ELECTRICAL CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified)				
PARAMETER	SYMBOL	TEST CONDITIONS	TYP.	UNITS
Resistance	R	$T_J = 25\text{ }^\circ\text{C}$	5000	$\Omega$
B Value	B	$T_J = 125\text{ }^\circ\text{C}/50\text{ }^\circ\text{C}$	3375	K

<b>MECHANICAL SPECIFICATIONS</b>						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS	
Junction to case Q1, Q2 POWER MOSFET thermal resistance (per switch)	$R_{thJC}$	-	-	0.44	$^\circ\text{C}/\text{W}$	
Junction to case Q3, Q4 WARP IGBT thermal resistance (per switch)		-	-	0.59		
Junction to case D1, D2, AP diode of WARP IGBT thermal resistance (per diode)		-	-	0.87		
Case to sink, flat, greased surface (per module)	$R_{thCS}$	-	0.05	-		
Mounting torque $\pm 10\%$ to heatsink <sup>(1)</sup>		-	-	4	Nm	
Weight		-	65	-	g	

**Note**

<sup>(1)</sup> A mounting compound is recommended and the torque should be rechecked after a period of 3 hours to allow for the spread of the compound. Lubricated threads.

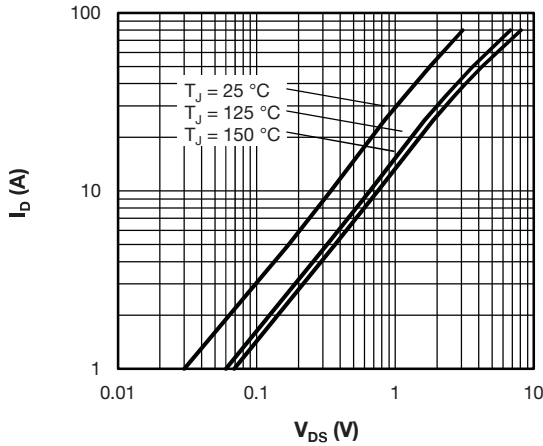


Fig. 1 - Power MOSFET Q1 - Q2 Typical Output Characteristics,  $V_{GS} = 10\text{ V}$

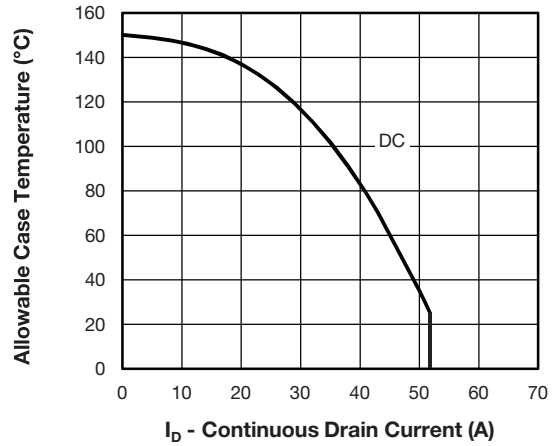


Fig. 4 - Power MOSFET Q1 - Q2 Maximum Continuous Drain Current vs. Case Temperature,  $V_{GS} = 10\text{ V}$

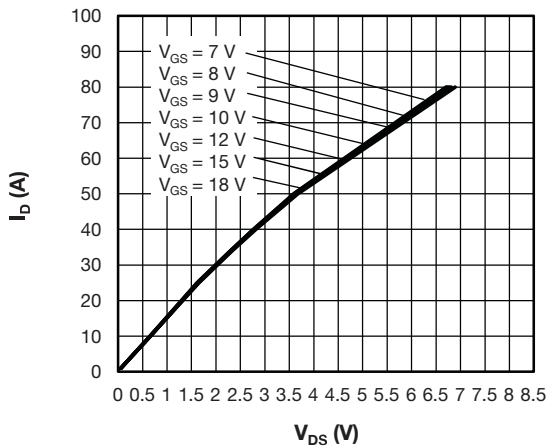


Fig. 2 - Power MOSFET Q1 - Q2 Typical Output Characteristics,  $T_J = 125\text{ °C}$

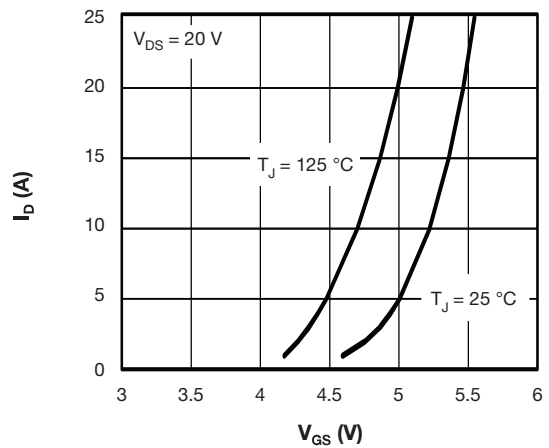


Fig. 5 - Power MOSFET Q1 - Q2 Typical Transfer Characteristics

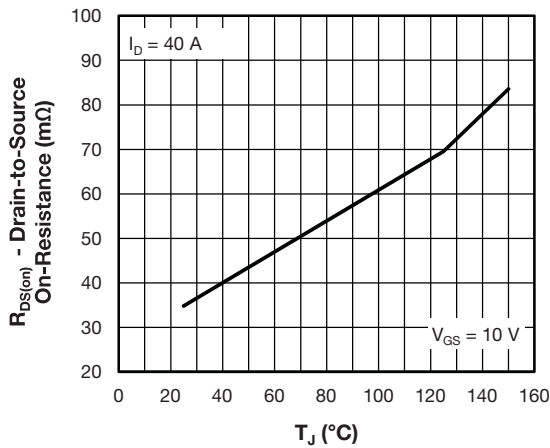


Fig. 3 - Power MOSFET Q1 - Q2 Typical Drain-to-Source On-Resistance vs. Temperature

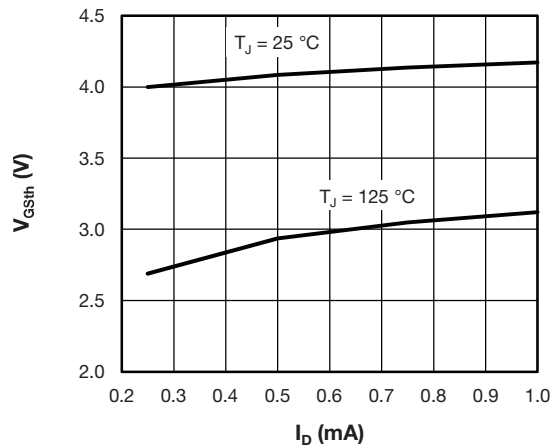


Fig. 6 - Power MOSFET Q1 - Q2 Typical Gate Threshold Voltage

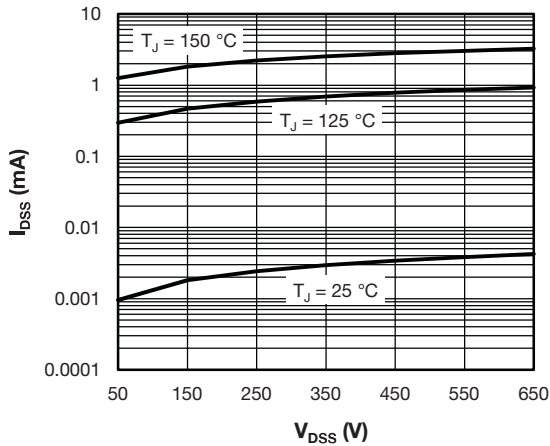


Fig. 7 - Power MOSFET Q1 - Q2 Typical Zero Gate Voltage Drain Current

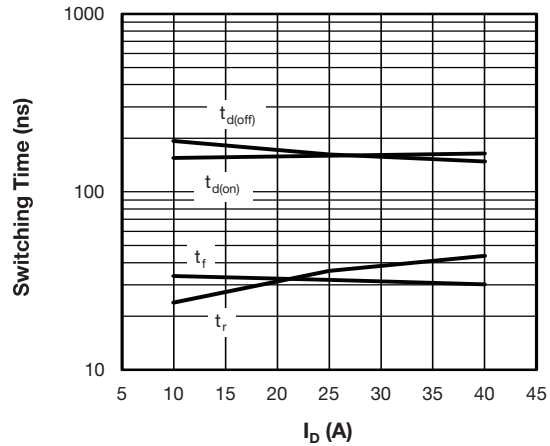


Fig. 9 - Power MOSFET Q1 - Q2 Typical Switching Time vs.  $I_D$  (with freewheeling diode 15ETH06),  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 325\text{ V}$ ,  $R_g = 5\ \Omega$ ,  $V_{GS} = 10\text{ V}$ ,  $L = 500\ \mu\text{H}$

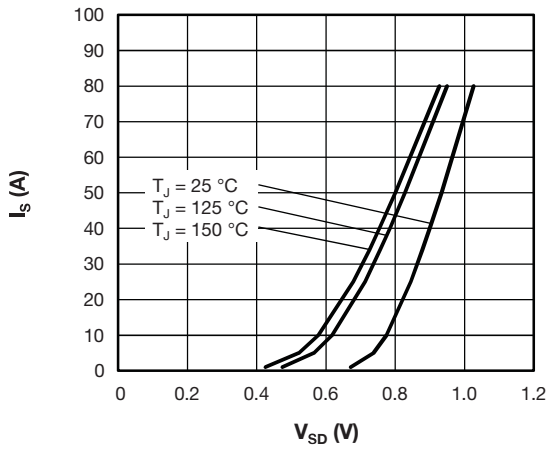


Fig. 8 - Power MOSFET Q1 - Q2 Typical Bodydiode Source-to-Drain Current Characteristics

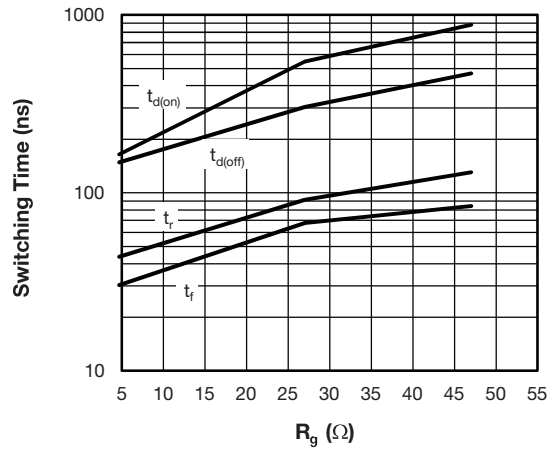


Fig. 10 - Power MOSFET Q1 - Q2 Typical Switching Time vs.  $R_g$  (with freewheeling diode 15ETH06),  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 325\text{ V}$ ,  $I_D = 40\text{ A}$ ,  $V_{GS} = 10\text{ V}$ ,  $L = 500\ \mu\text{H}$

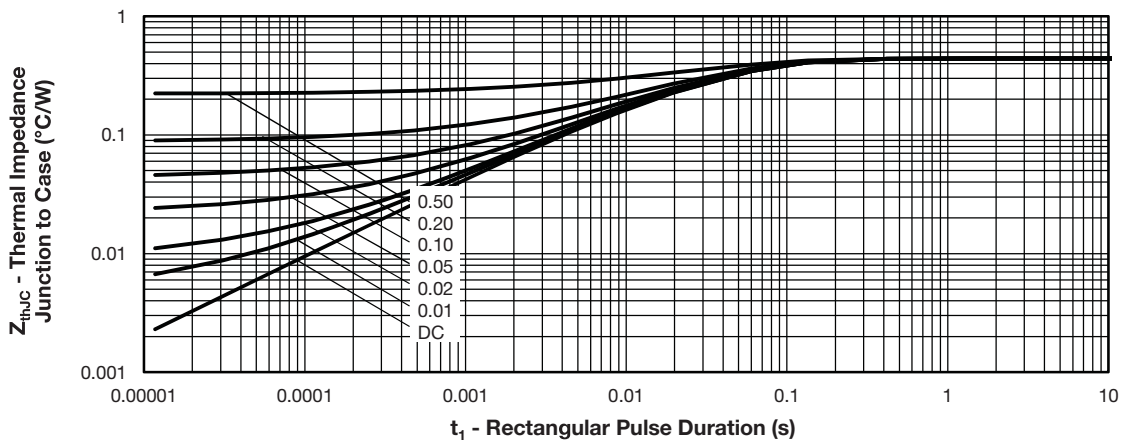


Fig. 11 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (Q1 - Q2 Power MOSFET)

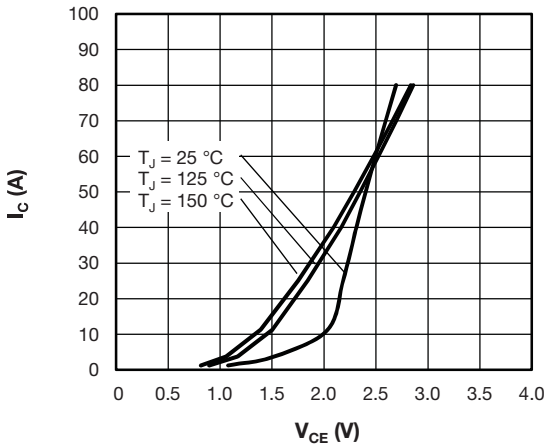


Fig. 12 - Q3 - Q4 IGBT Typical Output Characteristics,  $V_{GE} = 15\text{ V}$

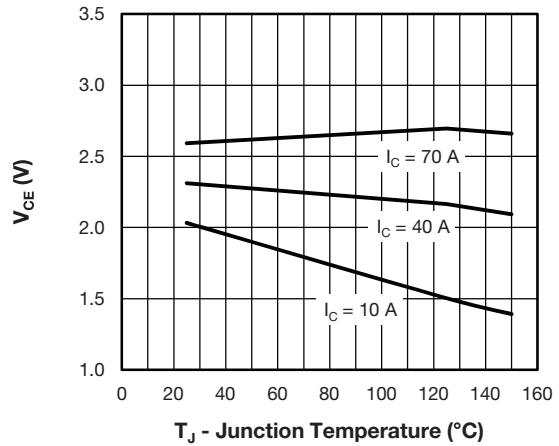


Fig. 15 - Q3 - Q4 IGBT Typical Collector to Emitter Voltage vs. Junction Temperature,  $V_{GE} = 15\text{ V}$

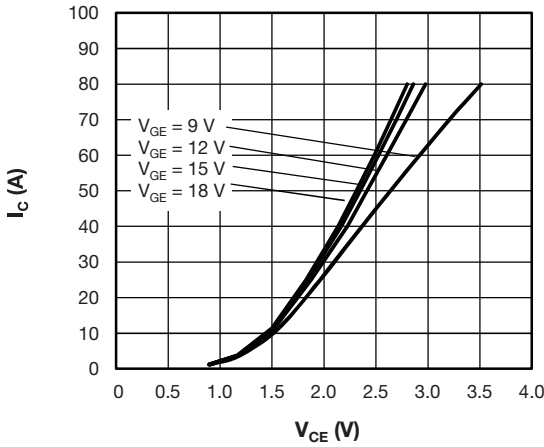


Fig. 13 - Q3 - Q4 IGBT Typical Output Characteristics,  $T_J = 125\text{ °C}$

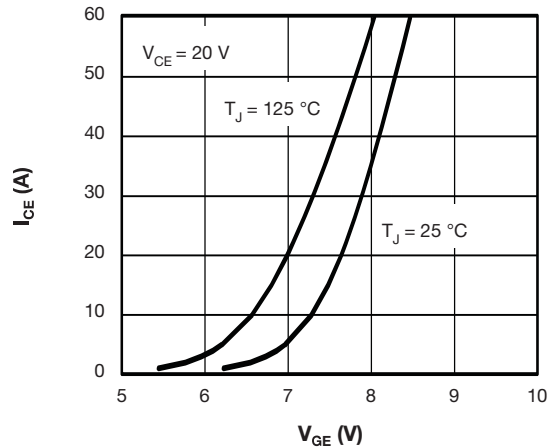


Fig. 16 - Q3 - Q4 IGBT Typical Transfer Characteristics

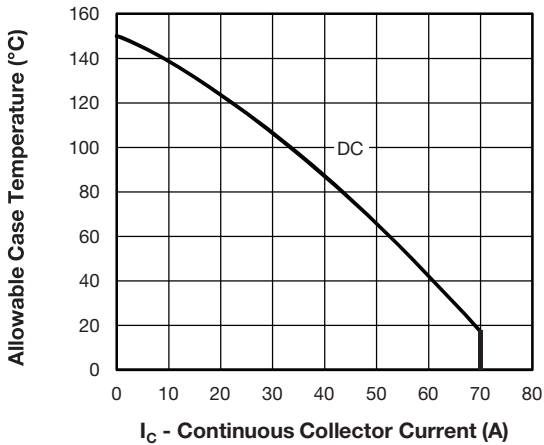


Fig. 14 - Q3 - Q4 IGBT Maximum Continuous Collector Current vs. Case Temperature

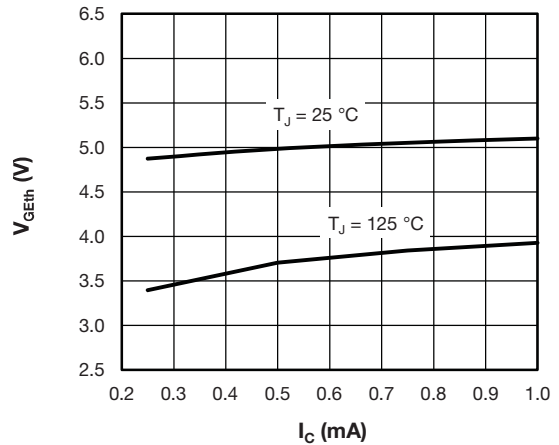


Fig. 17 - Q3 - Q4 IGBT Typical Gate Threshold Voltage

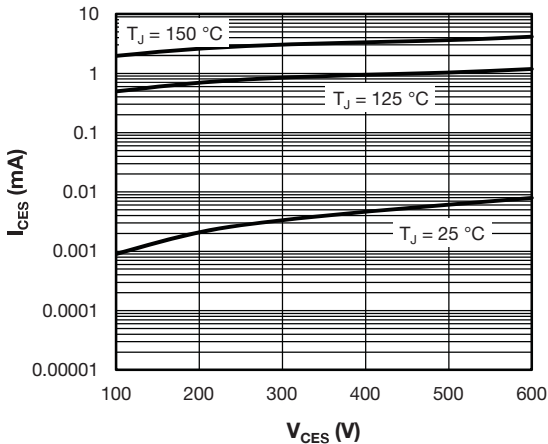


Fig. 18 - Q3 - Q4 IGBT Typical Trench Zero Gate Voltage Collector Current

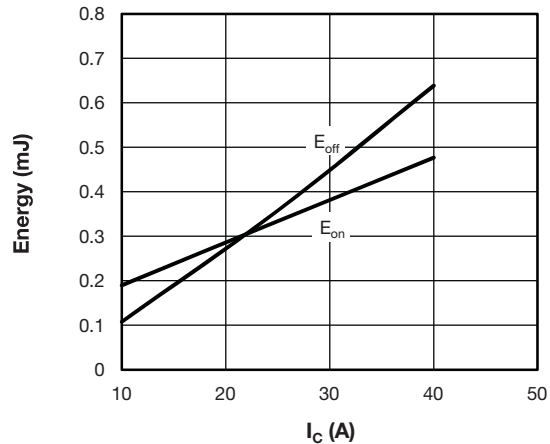


Fig. 21 - Q3 - Q4 IGBT Typical Energy Loss vs.  $I_C$  (with freewheeling D1 - D2 antiparallel diode),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 400\text{ V}$ ,  $R_g = 5\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

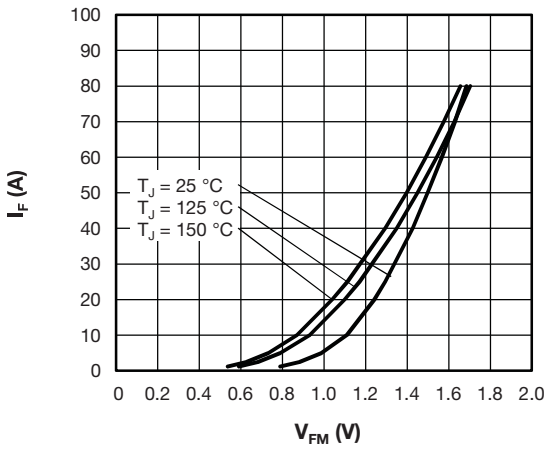


Fig. 19 - D1 - D2 Antiparallel Diode Typical Forward Characteristics

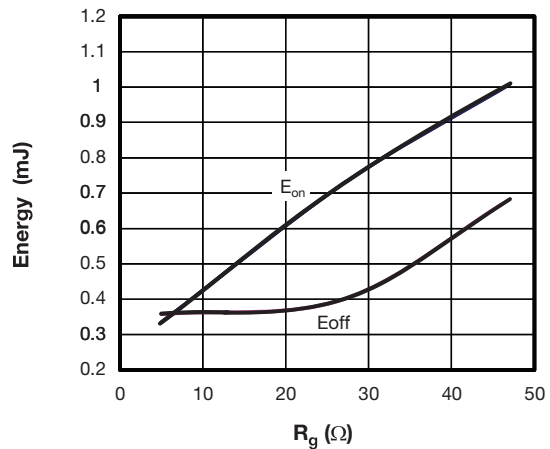


Fig. 22 - Q3 - Q4 IGBT Typical Energy Loss vs.  $R_g$  (with freewheeling D1 - D2 antiparallel diode),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 400\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$ ,  $I_C = 25\text{ A}$

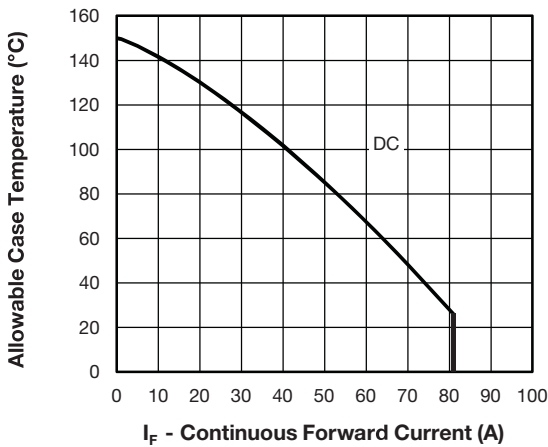


Fig. 20 - D1 - D2 Antiparallel Diode Maximum Forward Current vs. Case Temperature

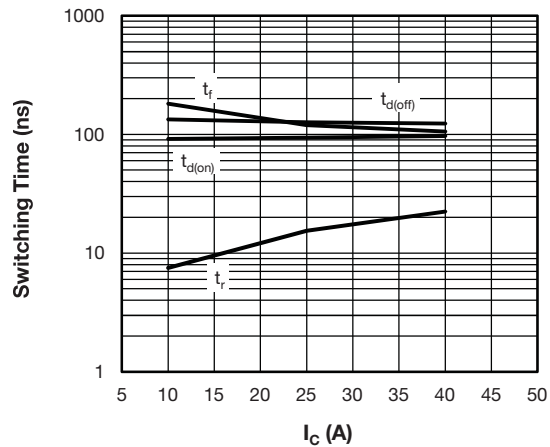


Fig. 23 - Q3 - Q4 IGBT Typical Switching Time vs.  $I_C$  (with freewheeling D1 - D2 antiparallel diode),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 400\text{ V}$ ,  $R_g = 5\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

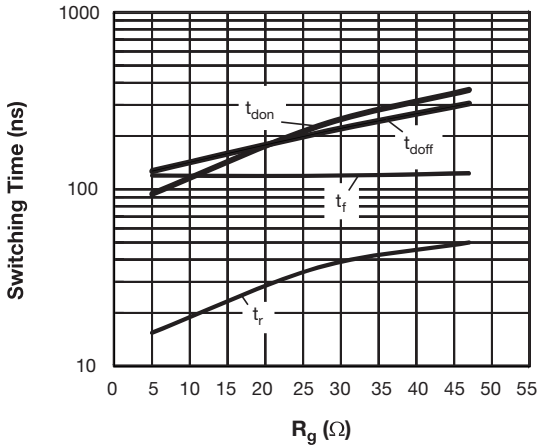


Fig. 24 - Q3 - Q4 IGBT Typical Switching Time vs.  $R_g$  (with freewheeling D1 - D2 antiparallel diode),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 400\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\text{ }\mu\text{H}$ ,  $I_C = 25\text{ A}$

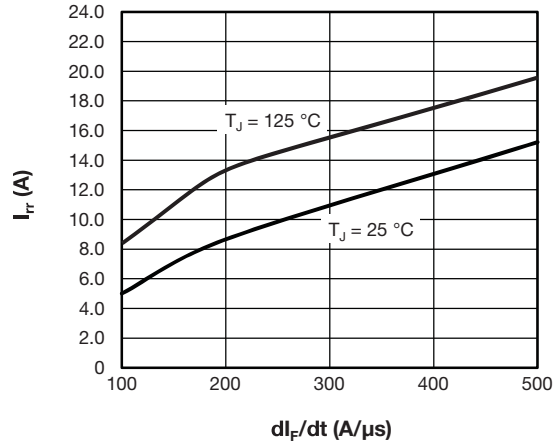


Fig. 26 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Current vs.  $dI_F/dt$ ,  $V_{RR} = 400\text{ V}$ ,  $I_F = 25\text{ A}$

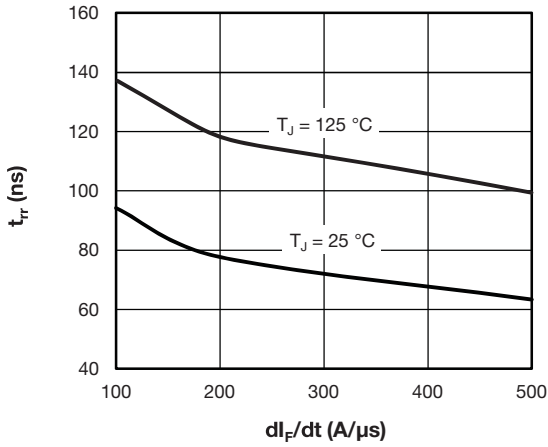


Fig. 25 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Time vs.  $dI_F/dt$ ,  $V_{RR} = 400\text{ V}$ ,  $I_F = 25\text{ A}$

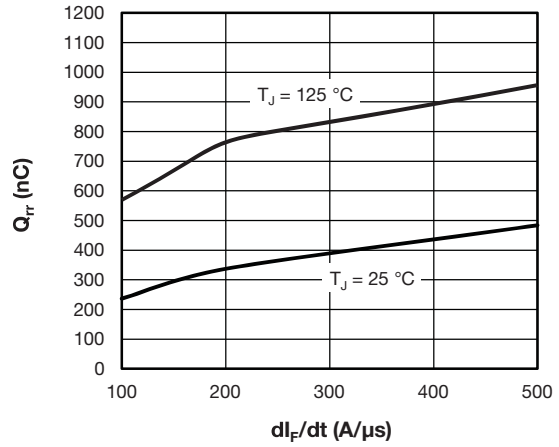


Fig. 27 - D1 - D2 Antiparallel Diode Typical Reverse Recovery Charge vs.  $dI_F/dt$ ,  $V_{RR} = 400\text{ V}$ ,  $I_F = 25\text{ A}$

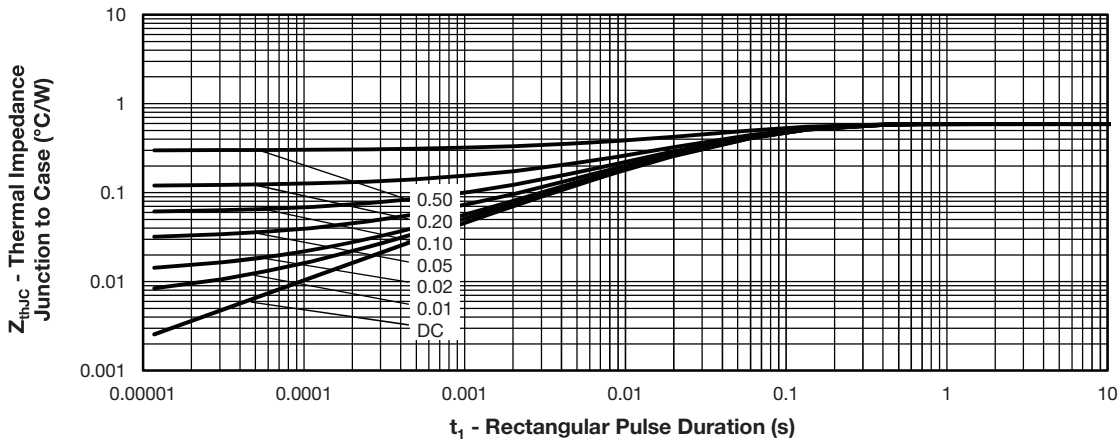


Fig. 28 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (Q1 - Q2 WARP IGBT)



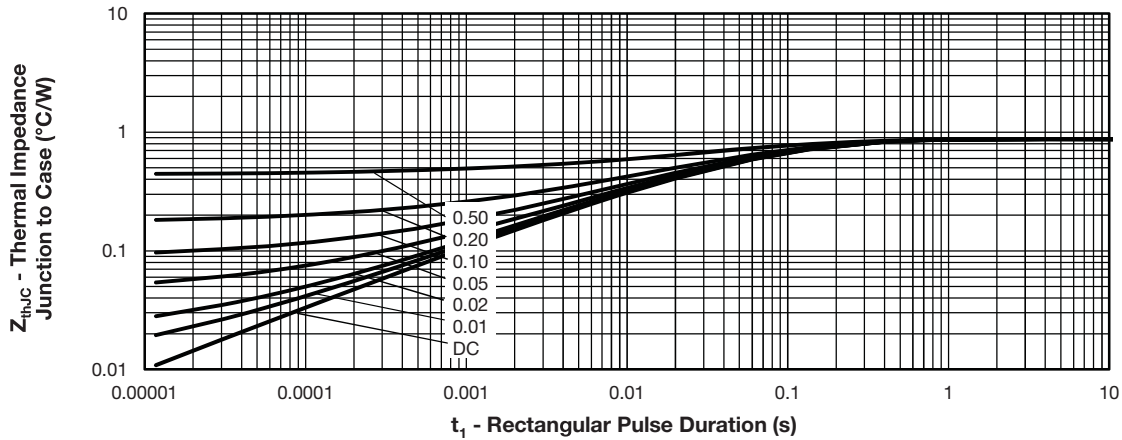


Fig. 29 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D1 - D2 Antiparallel Diode)

**ORDERING INFORMATION TABLE**

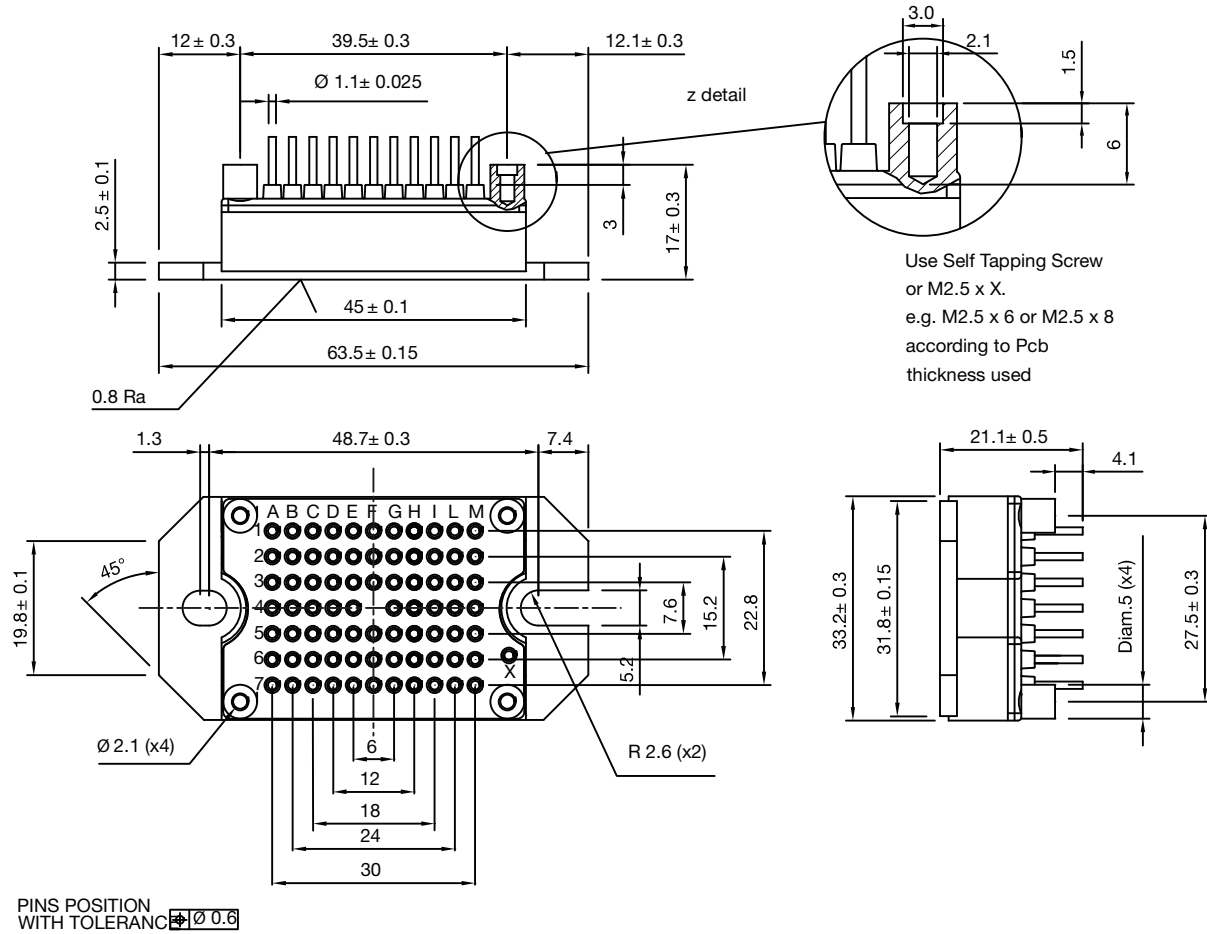
Device code	<b>VS-</b>	<b>40</b>	<b>MT</b>	<b>060</b>	<b>W</b>	<b>FH</b>	<b>T</b>
	①	②	③	④	⑤	⑥	⑦

- 1** - Vishay Semiconductors Product
- 2** - Current rating (40 = 40 A)
- 3** - MTP package
- 4** - Voltage code (060 = 600 V)
- 5** - Speed/type (W = Warp IGBT)
- 6** - Circuit configuration (FH = Full bridge MOSFET, IGBT)
- 7** - Thermistor

CIRCUIT CONFIGURATION		
CIRCUIT	CIRCUIT CONFIGURATION CODE	CIRCUIT DRAWING
Full bridge MOSFET, IGBT	FH	



### DIMENSIONS in millimeters





## Disclaimer

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